

L Number	Hits	Search Text	DB	Time stamp
17	3923	(photosensitive or (resist near4 film\$1)) and (mask\$4 or pattern\$1) and (substrate\$1 or workpiece\$1) and ((deposit\$4 or eject\$4) with (ink\$1 or liquid\$1 or fluid\$1))	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/01/16 12:54
18	306	((photosensitive or (resist near4 film\$1)) and (mask\$4 or pattern\$1) and (substrate\$1 or workpiece\$1) and ((deposit\$4 or eject\$4) with (ink\$1 or liquid\$1 or fluid\$1))) and ((photosensitive or (resist near4 film\$1)) same (mask\$4 or pattern\$1) same ((deposit\$4 or eject\$4) with (ink\$1 or liquid\$1 or fluid\$1)))	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/01/16 13:01
20	42	((photosensitive or (resist near4 film\$1)) and (mask\$4 or pattern\$1) and (substrate\$1 or workpiece\$1) and ((deposit\$4 or eject\$4) with (ink\$1 or liquid\$1 or fluid\$1))) and ((photosensitive or (resist near4 film\$1)) same (mask\$4 or pattern\$1) same ((deposit\$4 or eject\$4) with (ink\$1 or liquid\$1 or fluid\$1)))) and (347/\$.cccls.)	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/01/16 13:01
27	25	((photosensitive or (resist near4 film\$1)) and (mask\$4 or pattern\$1) and (substrate\$1 or workpiece\$1) and ((deposit\$4 or eject\$4) with (ink\$1 or liquid\$1 or fluid\$1))) and ((photosensitive or (resist near4 film\$1)) same (mask\$4 or pattern\$1) same ((deposit\$4 or eject\$4) with (ink\$1 or liquid\$1 or fluid\$1)))) and (347/\$.cccls.) and align\$4	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/01/16 13:01
28	13	((photosensitive or (resist near4 film\$1)) and (mask\$4 or pattern\$1) and (substrate\$1 or workpiece\$1) and ((deposit\$4 or eject\$4) with (ink\$1 or liquid\$1 or fluid\$1))) and ((photosensitive or (resist near4 film\$1)) same (mask\$4 or pattern\$1) same ((deposit\$4 or eject\$4) with (ink\$1 or liquid\$1 or fluid\$1)))) and (347/\$.cccls.) and align\$4) and mov\$4	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/01/16 13:03
29	8	((photosensitive or (resist near4 film\$1)) and (mask\$4 or pattern\$1) and (substrate\$1 or workpiece\$1) and ((deposit\$4 or eject\$4) with (ink\$1 or liquid\$1 or fluid\$1))) and ((photosensitive or (resist near4 film\$1)) same (mask\$4 or pattern\$1) same ((deposit\$4 or eject\$4) with (ink\$1 or liquid\$1 or fluid\$1)))) and (347/\$.cccls.) and align\$4) and mov\$4) and rotat\$4	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/01/16 13:02

30	34	((photosensitive or (resist near4 film\$1)) and (mask\$4 or pattern\$1) and (substrate\$1 or workpiece\$1) and ((deposit\$4 or eject\$4) with (ink\$1 or liquid\$1 or fluid\$1))) and ((photosensitive or (resist near4 film\$1)) same (mask\$4 or pattern\$1) same ((deposit\$4 or eject\$4) with (ink\$1 or liquid\$1 or fluid\$1))) and (347/.ccls.) not ((((((photosensitive or (resist near4 film\$1)) and (mask\$4 or pattern\$1) and (substrate\$1 or workpiece\$1) and ((deposit\$4 or eject\$4) with (ink\$1 or liquid\$1 or fluid\$1))) and ((photosensitive or (resist near4 film\$1)) same (mask\$4 or pattern\$1) same ((deposit\$4 or eject\$4) with (ink\$1 or liquid\$1 or fluid\$1))) and (347/.ccls.) and align\$4) and mov\$4) and rotat\$4)	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/01/16 13:03
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